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**Foz do Iguacu, Brazil
6 – 8 April 2016**



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Wednesday, 6th April 2016

08:00 - 09:00 Registration

09:00 - 09:20 Opening Session

General Chairs:

Letícia Maria Bolzani Poehls – PUCRS, Brazil;
Yervant Zorian – Synopsys, USA

Program Chairs:

Matteo Sonza Reorda – Politecnico di Torino, Italy;
Tiago Balen – UFRGS, Brazil

09:20 - 10:00 Keynote Talk

The Hype, Myths, and Realities of Testing 2.5D/3D Integrated Circuits1

Krishnendu Chakrabarty – Duke University, USA
Chair: Bernd Becker – University of Freiburg, Germany

10:00 - 10:20 Coffee Break

10:20 - 11:00 Session 1

Fault Tolerant Architectures

Chair: Mario Schölzel – IHP, Germany

On the Analysis of the Effects of Soft Errors on Compression Algorithms14

Massimo VIOLANTE, Matteo SONZA REORDA,
Serhiy AVRAMENKO (Politecnico di Torino, Italy),
G. FEY (DLR, Germany)

A Comprehensive Approach to Fault Tolerance (Invited presentation)20

Zoran STAMENKOVIC, Vladimir PETROVIC (IHP,
Germany)

11:00 - 12:00 Session 2

Microprocessor Test and Reliability

Chair: Fernanda Kastensmidt – UFRGS, Brazil

Auxiliary IP Blocks for Early Dependability Analysis of Small Processor based Systems....21

Jorge BARBOZA, Jose BASUALDO, Julio PEREZ
(Universidad de la Republica, Uruguay)

Dependability Evaluation of COTS Microprocessors via On-Chip Debugging Facilities27

Jose ISAZA-GONZALEZ, Alejandro SERRANO-
CASES (University of Alicante, Spain), Felipe
RESTREPO-CALLE (Universidad Nacional de
Colombia, Colombia), Sergio CUENCA-ASENSI,
Antonio MARTÍNEZ-ÁLVAREZ (University of
Alicante, Spain)

A Comprehensive Software-Based Self- Test and Self-Repair Method for Statically Scheduled Superscalar Processors33

Mario SCHÖLZEL (IHP and University of Potsdam,
Germany)

12:00 - 13:40 Lunch

13:40 - 14:20 Invited Talk

Accessing On-Chip Instruments through the System's Life-Time2

Erik Larsson – Lund University, Sweden
Chair: Francisco Russi – Synopsys, USA

14:20 - 15:20 Session 3

Fault Modeling and Simulation

Chair: Victor Champac – INAOE, Mexico

A Probabilistic Model for Stuck-On Faults in Combinational Logic Gates39

Rafael SCHIVITZ (FURG, Brazil), Denis FRANCO
(UFPEL, Brazil), Cristina MEINHARDT (FURG,
Brazil), Paulo BUTZEN (FURG, Brazil)

Fault model qualification by assertion mining....45

Graziano PRAVADELLI, Alessandro DANESE
(University of Verona, Italy)

A Control Path Aware Metric for Grading Functional Test Vectors51

Kelson GENT (Virginia Polytechnic Institute and
State University, USA), Michael HSIAO (Virginia
Tech, USA)

15:20 - 15:40 Coffee Break

15:40 - 16:40 Session 4

Fault Tolerance in SoCs and NoCs

Chair: Robert Aitken – ARM, USA

On the Consolidation of Mixed Criticalities Applications on Multicore Architectures57

Massimo VIOLANTE, Stefano ESPOSITO, Serhiy
AVRAMENKO (Politecnico di Torino, Italy)

Using Traffic Monitors to Tolerate Multiple Faults in 3D NoCs63

Anelise KOLOGESKI, Henrique Colao ZANUZ,
Fernanda KASTENSMIDT (UFRGS, Brazil)

On-line Fault Classification and Handling in IEEE 1687 Based Fault Management System for Complex SoCs69

Konstantin SHIBIN (Tallinn University of
Technology, Estonia), Artur JUTMAN (Testonica
Lab, Estonia), Sergei DEVADZE (Tallinn University
of Technology, Estonia)

16:40 - 17:40 Session 5

NBTI Modeling and Mitigation

Chair: *Zoran Stamenkovic – IHP, Germany*

Gate-Level Modelling of NBTI-Induced Delays under Process Variations75

Thiago Santos COPETTI, Guilherme MEDEIROS, Leticia BOLZANI POEHLS, Fabian VARGAS (PUCRS, Brazil), Sergei KOSTIN, Maksim JENIHHIN, Jaan RAIK, Raimund UBAR (Tallinn University of Technology, Estonia)

A Methodology to Assure Circuit Reliability at Reduced Power Consumption using Dual Supply Voltage81

Freddy FORERO, Andres GOMEZ, Victor CHAMPAC (INAOE, Mexico)

Analyzing NBTI Impact on SRAM Cells with Resistive-Open Defects87

Marco MARTINS, Guilherme CARDOSO MEDEIROS, Thiago Santos COPETTI, Fabian VARGAS, Leticia Maria BOLZANI POEHLS (PUCRS, Brazil)

17:40 - 18:40 Panel 1

Radiation Facilities in South America

Organizers: *Raoul Velazco (INPG, TIMA, France) and Fernanda Kastensmidt (UFRGS, Brazil)*

panelists: Raoul VELAZCO (INPG, TIMA, France), Nahuel VEGA (CONAE, Argentina), Fernanda KASTENSMIDT (UFRGS, Brazil) and Fabian VARGAS (PUCRS, Brazil)

18:40 - 19:20 LA TTTC Meeting *

* open, optional activity

20:00 - 22:00 Welcome Cocktail

Thursday, 7th April 2016

09:00 - 09:40 Invited Talk

Known Unknowns - Knowledge in the Presence of Unknowns5

Bernd Becker - University of Freiburg, Germany

Chair: *Hans-Joachim Wunderlich – University of Stuttgart, Germany*

09:40 - 10:20 Session 6

Soft Errors in Memory and Processors

Chair: *Fabian Vargas – PUCRS, Brazil*

Evaluating the Effects of Single Event Upsets in Soft-core GPGPUs93

Werner NEDEL, Fernanda KASTENSMIDT (UFRGS, Brazil), José AZAMBUJA (FURG, Brazil)

Hybrid Soft Error Mitigation Techniques for COTS Processor-based Systems99

Eduardo CHIELLE (UFRGS, Brazil), Boyang DU (Politecnico di Torino, Italy), Fernanda KASTENSMIDT (UFRGS, Brazil), Sergio CUENCA-ASENSI (University of Alicante, Spain), Luca STERPONE, Matteo SONZA REORDA (Politecnico di Torino, Italy)

10:20 - 10:40 Coffee Break

10:20 - 11:00 Poster Session

Chair: *Leticia Maria Bolzani Poehls – PUCRS, Brazil*

On Automatic Software-Based Self-Test Program Generation Based on High-Level Decision Diagrams177

Artjom JASNETSKI, Raimund UBAR, Anton TSERTOV (Tallinn University of Technology, Estonia)

A Deep Analysis of SEU Consequences in the Internal Memory of LEON3 Processor178

Raoul VELAZCO, Afef KCHAOU (TIMA, France), Wajih EL HADJ YOUSSEF (LEME, Tunisia), Fraidy BOUESSE, Pablo RAMOS (TIMA, France)

Software Errors Analysis at the Zynq SoC ARM Embedded Processor179

Gennaro RODRIGUES, Fernanda KASTENSMIDT (UFRGS, Brazil)

Reliability Analysis of Majority Voters under Permanent Faults180

Eduardo LIEBL, Cristina MEINHARDT, Paulo BUTZEN (FURG, Brazil)

Single Trojan Injection Model Generation and Detection181

Daniel SAAB (CWRU, USA), Jacob ABRAHAM (University of Texas, USA), Harini BHAMIDIPATI (LSI Logic, USA)

Checksum Based Error Detection in Linearized Representations of Non Linear Control Systems....182

Suvadeep BANERJEE, Abhijit CHATTERJEE (Georgia Institute of Technology, USA), Jacob ABRAHAM (University of Texas, USA)

11:00 - 12:00 Session 7

Radiation Effects and Mitigation

Chair: *Raoul Velazco – INPG and TIMA, France*

Radiation Effects in Low Power and Ultra Low Power Voltage References111

Daniel FUSCO, Tiago BALEN (UFRGS, Brazil)

Fault Simulation in Radiation-Hardened SOI CMOS VLSIs using Universal Compact MOSFET Model117

Konstantin PETROSYANTS, Lev SAMBURSKY, Igor KHARITONOV, Boris LVOV (Moscow Institute of Electronics and Mathematics of National Research University “Higher School of Economics”, Russia)

Performance Evaluation of Radiation Hardened Analog Circuits based on Enclosed Layout Geometry123

Guilherme CARDOSO, Tiago BALEN (UFRGS, Brazil)

12:00 - 13:00 Panel 2

Hardware Security and Trust

Organizers: Ramesh Karri (Polytechnic School of Engineering, New York University, USA) and Ozgur Sinanoglu (New York University in Abu Dhabi, UAE)

Coordinator: Fabian Vargas (PUCRS, Brazil)

Panelists: Michail MANIATAKOS (New York University Abu Dhabi, UAE), Krishnendu Chakrabarty (Duke University, USA), and Yervant Zorian (Synopsys, USA)

13:00 - 14:30 Lunch

14:30 - 18:30 Social Event

20:30 - 23:30 Gala Dinner

Friday, 8th April 2016

09:00 - 09:40 Invited Talk

Transforming Nanodevices into Nanosystems: The N3XT 1,000X6

Subhasish Mitra – Stanford University, USA

Chair: Pierre-Emmanuel Gaillardon – University of Utah, USA

09:40 - 10:20 Session 8

Defect Based Test and Silicon Validation

Chair: Erik Larsson – Lund University, Sweden

Comparative study of Bulk, FDSOI and FinFET technologies in presence of a resistive short defect129

Amit KAREL, Mariane COMTE, Jean-Marc GALLIERE, Florence AZAIS, Michel RENOVELL (LIRMM, France)

On-Silicon Validation of a Benchmark Generation Methodology for Effectively Evaluating a Combinational Cell Library Design135

Mauricio CARVALHO, Mauricio ALTIERI, Lauro PURICELLI (UFRGS, Brazil), Paulo BUTZEN (FURG, Brazil), Renato RIBAS, Eric FABRIS (UFRGS, Brazil)

10:20 - 10:40 Coffee Break

10:40 - 11:40 Session 9

Embedded Systems and Software Reliability

Chair: Graziano Pravadelli – University of Verona, Italy

A Framework for Early Functional Verification of Embedded Software Combining Virtual Platforms and Bounded Model Checking141

Rogério PALUDO, Djones LETTNIN (UFSC, Brazil)

Soft Error Analysis in Embedded Software Developed with & without Operating System....147

Luiz CASAGRANDE, Fernanda KASTENSMIDT (UFRGS, Brazil)

A HW-dependent Software Model for Cross-Layer Fault Analysis in Embedded Systems153

Christian BARTSCH, Carlos VILLARRAGA, Dominik STOFFEL, Wolfgang KUNZ (University of Kaiserslautern, Germany)

11:40 - 12:20 Special Session 1

Dependable MPSoCs

Organizer: Fernando Gehm Moraes, (PUCRS, Brazil)

Dependable On-Chip Infrastructure for Dependable MPSOCs183

Michael A. KOCHTE, Hans-Joachim WUNDERLICH (University of Stuttgart, Germany)

A Layered Approach for Fault Tolerant NoC-Based MPSoCs189

Eduardo WACHTER, Francisco BARRETO, Vinicuis FOCHI, Alexandre M. AMORY, Fernando G. MORAES (PUCRS, Brazil)

12:20 - 14:00 Lunch

14:00 - 14:40 Invited Talk

Spin Transfer Torque Memories for On-chip Caches: Prospects and Perspectives7

Kaushik Roy – Purdue University, USA

Chair: Yervant Zorian – Synopsys, USA

14:40 - 15:20 Special Session 2

Emerging Nanotechnologies

Organizer: Subhasish Mitra (Stanford University, USA)

Three-Independent-Gate Transistors: Opportunities in Digital, Analog and RF Applications195

Pierre-Emmanuel GAILLARDON (University of Utah, USA)

Processor-Level Implications of Emerging Technologies

Robert AITKEN (ARM, USA)

15:20 - 16:30 PhD & Master Contests

TTTC's McCluskey Best 2016 Latin American PhD Thesis Contest

Master Thesis Contest

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16:30 - 16:50 Coffee Break

16:50 - 17:50 Session 10

Verification and System Level Testing

Chair: Jacob Abraham – University of Texas, USA

A SystemC-based Platform for Assertion-based Verification and Mutation Analysis in Systems Biology159

Nicola BOMBIERI (University of Verona, Italy),
Rosalba GIUGNO (University of Catania, Italy),
Franco FUMMI, Carlo LAUDANNA, Rosario DISTEFANO, Daniele COATI, Michela MIRENDA (University of Verona, Italy)

Infrastructure for Formal and Dynamic Verification of Peripheral Programming Model165

Walter ENCINAS, Francisco ARAUJO, Harney ABRAHIM (Freescale Semicondutores, Brazil)

System-Level Diagnosis for WSN: A Heuristic171

Mauricio BARROS, Andrea WEBER (UFPR, Brazil)

17:50 - 18:30 Closing Remarks

Award Ceremony for the PhD and Master Thesis Contests

Additional Papers

Proposal of a Functional Safety Methodology Applied to Fault Tolerance in FPGA Applications....8

B. F. Flesch, B. Brand, R. Marques de Figueiredo, L. R. Prade, M. Rosa da Silva (University of Bells River Valley, Brazil)

Attacking the Smart Grid using Public Information....105

C. Konstantinou (Polytechnic School of Engineering, New York University, USA)
M. Sazos (Center for Cyber Security, New York University in Abu Dhabi, UAE)
M. Maniatakos (New York University in Abu Dhabi, UAE)

Saturday, 9th April 2016

09:00 - 12:00 TTEP 1

Hierarchical Test for Today's SOC and IoT

Yervant Zorian - Synopsys, USA

14:00 - 17:00 TTEP 2

Combining Structural and Functional Test Approaches across System Levels

Artur Jutman - Testonica Lab, Estonia

Hans-Joachim Wunderlich - University of Stuttgart, Germany

Matteo Sonza Reorda - Politecnico di Torino, Italy

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